Product Update

FormFactor™

MPS150

150 mm Modular Probe Station

Customize your 150 mm probe station based on flexible modules at an incredible price!

FormFactor introduces a new modular concept for its best-in-class 150 mm probe stations. This will make it even easier to configure your individual probe solution for current and future needs at an incredible price. Simply choose a base station and add as many application-specific starter kits as you need.

Example: Complete 150 mm Entry-level IV/CV Manual Probe Station

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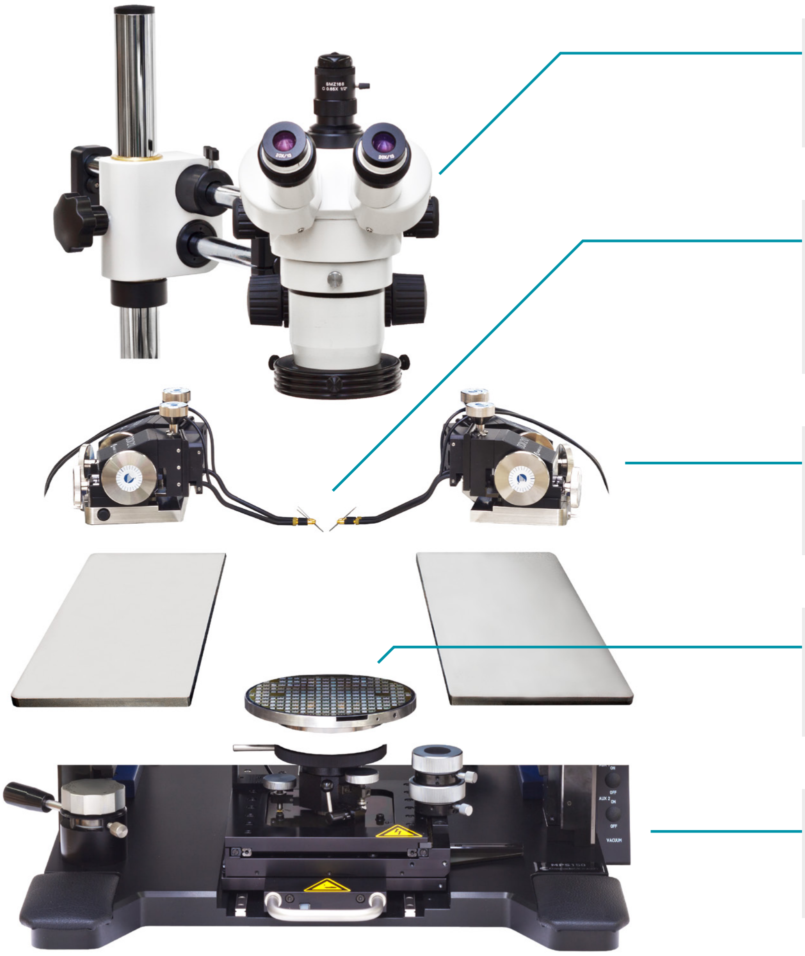


Microscope

Stereo Zoom / High Resolution

Application Starter Kit

IV/CV / RF / mmW / THz / Load-pull / Failure Analyis / High Power

Positioner Kit

Basic / Advanced

Chuck

Coax / Triax / RF / Thermal / High Power

Base Station

Basic / Advanced

** Price includes: 150 mm station, coaxial chuck, stereo zoom microscope, 4 DC positioners and probe tips. Excludes shipping and installation.*

Configuration Examples

Coax

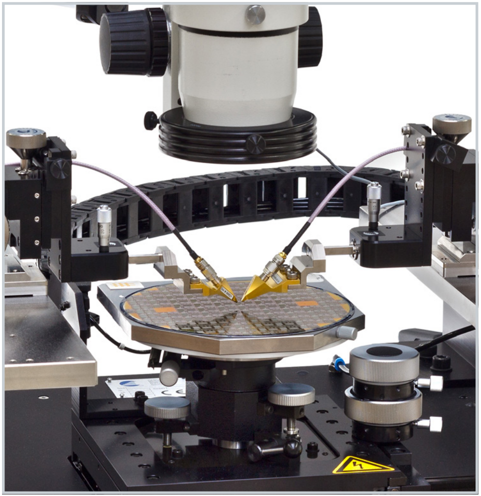
DC parametric test down to pA levels

- Movable platen with 40 mm height adjustment, 200 µm contact / separation stroke and ± 1 µm repeatability
- Chuck stage with adjustable friction & stage lock, unique Z chuck adjustment and 90 mm pull-out
- Magnetic positioners with 1 µm feature resolution and 3 linear axes with precision ball bearing

Triax

Low-noise measurements down to fA level

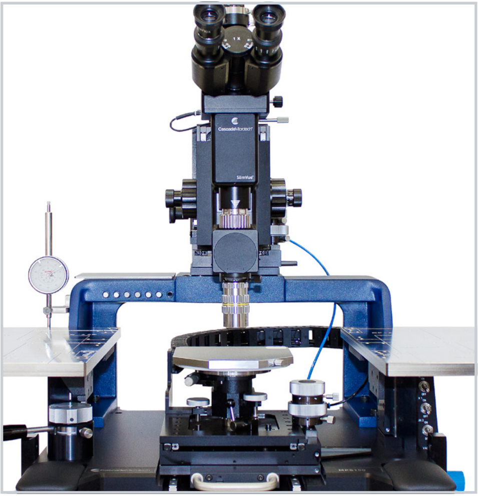
- Stereo microscope: 15x–100x magnification with large field-of-view and camera-ready c-mount
- Four triax probe arms and high-quality triax cables
- Light/EMI shielding (optional)
- Upgrade option for fF-level measurements
- TRIAX chuck with ±8 fine theta chuck rotation, three auxiliary areas, chuck surface with ±5 µm planarity for consistent contact force and overtravel
- East/West to North/South measurements with single setup



RF test up to 67 GHz

- Three probe technologies available: Infinity Probe, ACP Probe, |Z| Probe
- Matching cables and substrates included
- RF chuck ±3 µm surface planarity
- Unique 200 µm platen contact/ separation stroke with ≤± 1 µm accuracy for repeatable contact
- WinCal XE Calibration Software

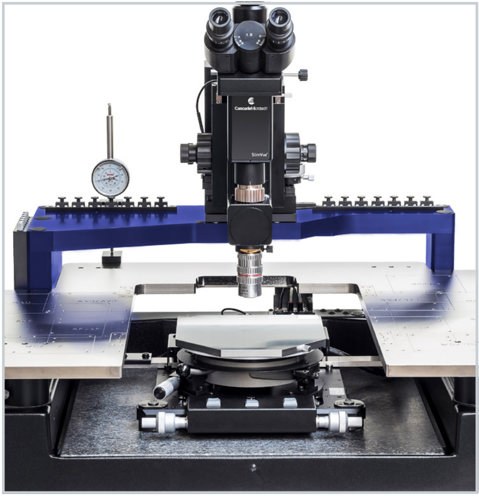
Configuration Examples (continued)



mmW - 70 GHz through sub-THz and load-pull

70 GHz through sub-THz and load-pull

- SlimVue microscope with quick lens exchange, 1 µm opitcal resolution, resolving ‹50 µm pads
- Engraved guides on mmW platen for application-specific SIGMA Kits
- Supports broadband, load pull, coax RF and banded waveguide configuration
- Optical feedback on platen position (gauge)
- Vibration Isolation Platform



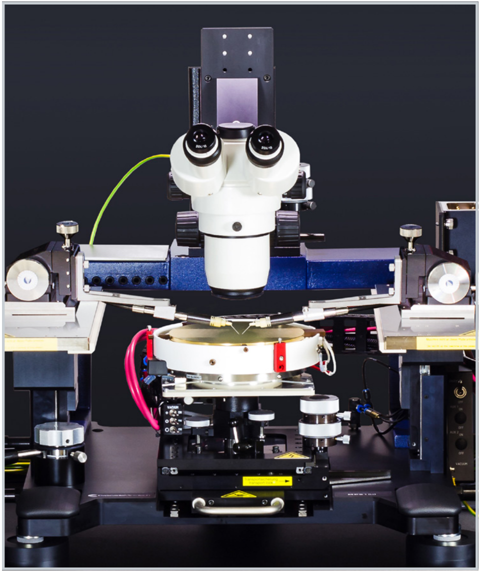
mmW probing up to THz and load-pull

- SlimVue microscope with quick lens exchange, 1 µm opitcal resolution, resolving ‹50 µm pads
- Engraved guides on mmW platen for application-specific SIGMA Kits
- Supports broadband, load pull, coax RF and banded waveguide configuration
- Optical feedback on platen position (gauge)
- Rock-solid mechanical design and vibration isolation platform
- Submicron stage accuracy
- Motorized positioners
- <+-1 µm separation repeatability
- Micrometer-accuracy and repeatable probe placement and over travel

Failure analysis and design debug

- Stable microscope bridge design and XY microscope with up to 4000x magnification (option)
- Laser cutter and camera ready
- Contact submicron features
- Simultaneous use of probe card and single needles (option)
- Chuck ready for single DUT
- Quickest transition from wafer-to-chip-to-package
- Vacuum positioners with 1 µm feature resolution
- DPP450 positioner with nanometer resolution and accuracy (option)

Configuration Examples (continued)



High Power

On-wafer power device characterization

- Multi-purpose SIGMA instrument integration kit
- Triax probe with protected guard
- Seamless integration of various analyzers
- Triax chuck with surface coating for low-leakage measurements up to 3 kV, high-isolation ready
- High-current measurements up to 100 A with lowest contact resistance
- Optional upgrade for 10 kV (coax) operating voltage
- Thin wafer handling capability
- Arcing protection and advanced grounding concept
- Shield Enclosure with interlock for EMI/light-tight environment
- Maximum protection from high-voltage shock for users and devices

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Educational Savings Program

Make the Most of Your Research Budget

With our Education Savings Program you can benefit from exclusive savings on 150 mm wafer probe systems.

Program Benefits*

- Free shipping
- 2-Year Factory Warranty
- 4 Years of Free WinCal XE™ Calibration Software Updates
- 10% Discount on Upgrades

**For terms and conditions, please contact your local sales representative or visit us at https://www.formfactor.com/download/educational-savings-program/*